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JOE 2	(PTO/SB	•	FILING DATE March 30, 2004		GROUP 2814			
OHAD		U.S. PATEI	NT DOCUMENTS					
EXAMINER'S INITIALS	PATENT NO.	. DATE	NAME	CLASS	SUBCLASS	FILING DATE		
WSL	2001/0002139	05-2001	Hiraoka, Keiko					
WSL	6,117,700	09-2000	Orita et al.					
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		FOREIGN PA	TENT DOCUMENTS					
EXAMINER'S INITIALS	AMINER'S PATENT NO DATE		COUNTRY	Abstract	Translation	Equivalent		
WSL	10/173224	6/1998	Japan		Х			
	09/129919	5/1997	Japan		X			
	10/173222	6/1998	Japan		X			
	2001-035796	2/2001	Japan		X			
	09-129933	5/1997	Japan .		х			
1/	10-341039	12/1998	Japan		X			
$\forall$	08-032115	2/1996	Japan		Х			
						<u> </u>		
	OTHE	R ART (Including Aut	hor, Title, Date, Pertine	nt Pages, Et	c.)			
	Patent Abstracts o	of Japan – Publication	No. 2001-035796, filed F	ebruary 9,	2001			
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

INFORMATION DISCLOSURE CITATION IN AN					ATTY. DOCKET 2336-257	U.S. PATENT APPLICATION NO. 10/811,808				
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	EXAMINER'S PATENT NO. DATE		C	OUNTRY	CLASS	SUBCLASS	Trans Yes	lation No		
W		10-173224	6/1998		Japan			X		
	i	09-129919	5/1997		Japan		İ	X		
		10-173222	6/1998		Japan			X		
		2001-035796	2/2001		Japan			X		
		09-129933	5/1997		Japan			X		
		10-341039	12/1998		Japan			X		
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INFORMATION DISCLOSURE CITATION IN AN APPLICATION				ATTY. DOCKET NO. 2336-257		U.S. APPLICATION NO. Not yet assigned		
				APPLICANT Seung Wan CHAE et al.				
(PTO-1449)				FILING DATE herewith		GROUP		
		U.S. PATENT	`DC	CUMENTS				
EXAMINER'S INITIALS	PATENT NO.	DATE		NAME CLASS SUBCLA			FILING DATE	
WSL	5,563,422	10/1996	Nakamura et al.					
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